

Notice of References Cited	Application/Control No. 10/669,997	Applicant(s)/Patent Under Reexamination DIDIER ET AL.	
	Examiner Paul D. Kim	Art Unit 3729	Page 1 of 1

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	C	US-2005/02313115	10-2005	Sentoku	335/302
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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